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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	800MHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8544vjanga

Figure 1 shows the MPC8544E block diagram.

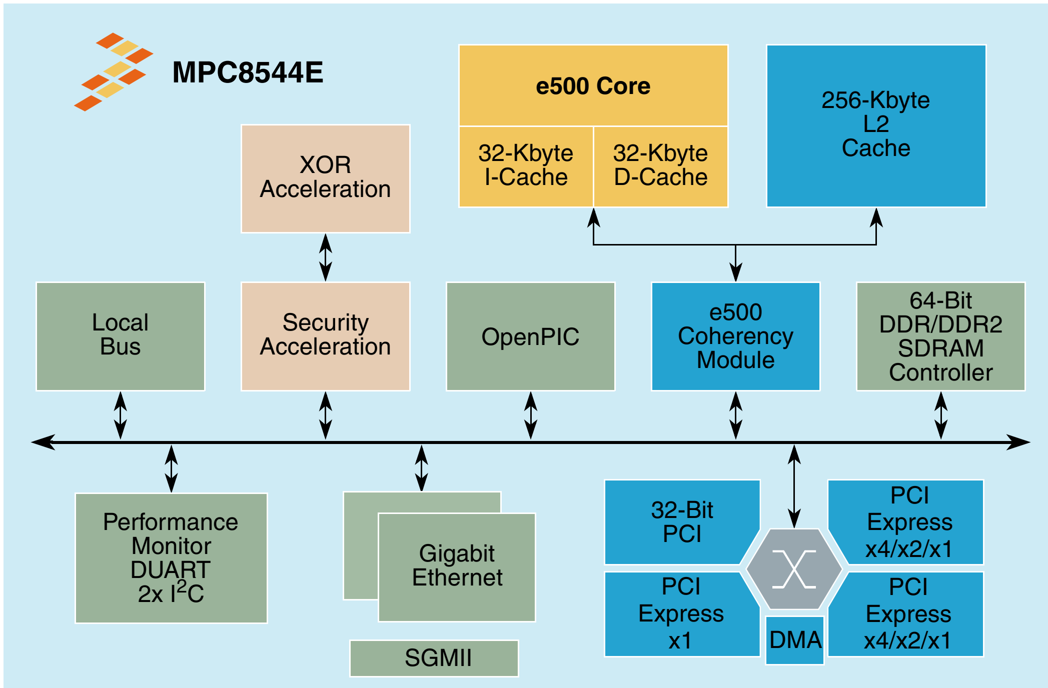


Figure 1. MPC8544E Block Diagram

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8544E. This device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings[1]

Characteristic	Symbol	Max Value	Unit	Notes
Core supply voltage	V_{DD}	–0.3 to 1.1	V	—
PLL supply voltage	AV_{DD}	–0.3 to 1.1	V	—
Core power supply for SerDes transceivers	SV_{DD}	–0.3 to 1.1	V	—
Pad power supply for SerDes transceivers	XV_{DD}	–0.3 to 1.1	V	—

Table 1. Absolute Maximum Ratings[1] (continued)

Characteristic		Symbol	Max Value	Unit	Notes
DDR and DDR2 DRAM I/O voltage		GV_{DD}	–0.3 to 2.75 –0.3 to 1.98	V	—
Three-speed Ethernet I/O, MII management voltage		LV_{DD} (eTSEC1)	–0.3 to 3.63 –0.3 to 2.75	V	—
		TV_{DD} (eTSEC3)	–0.3 to 3.63 –0.3 to 2.75	V	—
PCI, DUART, system control and power management, I^2C, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	—
Local bus I/O voltage		BV_{DD}	–0.3 to 3.63 –0.3 to 2.75 –0.3 to 1.98	V	—
Input voltage	DDR/DDR2 DRAM signals	MV_{IN}	–0.3 to (GV_{DD} + 0.3)	V	2
	DDR/DDR2 DRAM reference	MV_{REF}	–0.3 to (GV_{DD} + 0.3)	V	2
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	–0.3 to (LV_{DD} + 0.3) –0.3 to (TV_{DD} + 0.3)	V	2
	Local bus signals	BV_{IN}	–0.3 to (BV_{DD} + 0.3)	V	—
	DUART, SYSCLK, system control and power management, I^2C, and JTAG signals	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	2
	PCI	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	2
Storage temperature range		T_{STG}	–55 to 150	°C	—

Notes:

1. Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause.
2. (M,L,O)V_{IN}, and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.

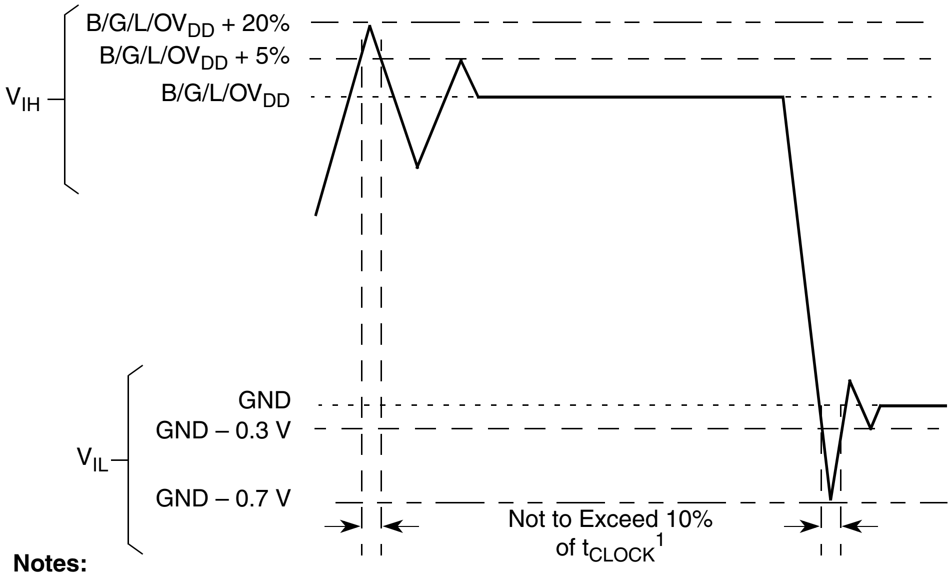
2.1.2 Recommended Operating Conditions

Table 2 provides the recommended operating conditions for this device. Note that the values in Table 2 are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic	Symbol	Recommended Value	Unit	Notes
Core supply voltage	V_{DD}	1.0 ± 50 mV	V	—
PLL supply voltage	AV_{DD}	1.0 ± 50 mV	V	1
Core power supply for SerDes transceivers	SV_{DD}	1.0 ± 50 mV	V	—
Pad power supply for SerDes transceivers	XV_{DD}	1.0 ± 50 mV	V	—
DDR and DDR2 DRAM I/O voltage	GV_{DD}	2.5 V ± 125 mV 1.8 V ± 90 mV	V	2

Figure 2 shows the undershoot and overshoot voltages at the interfaces of the MPC8544E.



Notes:

1. t_{CLOCK} refers to the clock period associated with the respective interface:
   For I^2C and JTAG, t_{CLOCK} references SYSCLK.
   For DDR, t_{CLOCK} references MCLK.
   For eTSEC, t_{CLOCK} references EC_GTX_CLK125.
   For LBIU, t_{CLOCK} references LCLK.
   For PCI, t_{CLOCK} references PCI_CLK or SYSCLK.
2. Please note that with the PCI overshoot allowed (as specified above), the device does not fully comply with the maximum AC ratings and device protection guideline outlined in Section 4.2.2.3 of the *PCI 2.2 Local Bus Specifications*.

Figure 2. Overshoot/Undershoot Voltage for GV_{DD}/OV_{DD}/LV_{DD}/BV_{DD}/TV_{DD}

The core voltage must always be provided at nominal 1.0 V (see Table 2 for actual recommended core voltage). Voltage to the processor interface I/Os are provided through separate sets of supply pins and must be provided at the voltages shown in Table 2. The input voltage threshold scales with respect to the associated I/O supply voltage. OV_{DD} and LV_{DD} based receivers are simple CMOS I/O circuits and satisfy appropriate LVCMOS type specifications. The DDR2 SDRAM interface uses a single-ended differential receiver referenced the externally supplied MV_{REF} signal (nominally set to GV_{DD}/2) as is appropriate for the SSTL2 electrical signaling standard.

4.5 Other Input Clocks

For information on the input clocks of other functional blocks of the platform such as SerDes, and eTSEC, see the specific section of this document.

5 RESET Initialization

This section describes the AC electrical specifications for the RESET initialization timing requirements of the MPC8544E. Table 8 provides the RESET initialization AC timing specifications for the DDR SDRAM component(s).

Table 8. RESET Initialization Timing Specifications[1]

Parameter/Condition	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HREST}}$	100	—	µs	—
Minimum assertion time for $\overline{\text{SRESET}}$	3	—	SYSCLKs	1
PLL input setup time with stable SYSCLK before $\overline{\text{HRESET}}$ negation	100	—	µs	—
Input setup time for POR configs (other than PLL config) with respect to negation of $\overline{\text{HRESET}}$	4	—	SYSCLKs	1
Input hold time for all POR configs (including PLL config) with respect to negation of $\overline{\text{HRESET}}$	2	—	SYSCLKs	1
Maximum valid-to-high impedance time for actively driven POR configs with respect to negation of $\overline{\text{HRESET}}$	—	5	SYSCLKs	1

Note:
1. SYSCLK is the primary clock input for the MPC8544E.

Table 9 provides the PLL lock times.

Table 9. PLL Lock Times

Parameter/Condition	Min	Max	Unit	Notes
Core and platform PLL lock times	—	100	µs	—
Local bus PLL	—	50	µs	—
PCI bus lock time	—	50	µs	—

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR SDRAM interface of the MPC8544E. Note that DDR SDRAM is GV_{DD}(typ) = 2.5 V and DDR2 SDRAM is GV_{DD}(typ) = 1.8 V.

Table 16 provides the input AC timing specifications for the DDR SDRAM when GV_{DD}(typ) = 2.5 V.

Table 16. DDR SDRAM Input AC Timing Specifications for 2.5-V Interface

At recommended operating conditions.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MV_{REF} – 0.31	V	—
AC input high voltage	V_{IH}	MV_{REF} + 0.31	—	V	—

Table 17 provides the input AC timing specifications for the DDR SDRAM interface.

Table 17. DDR SDRAM Input AC Timing Specifications

At recommended operating conditions.

Parameter	Symbol	Min	Max	Unit	Notes
Controller skew for MDQS—MDQ/MECC/MDM	t_{CISKEW}			ps	1, 2
533 MHz		–300	300		3
400 MHz		–365	365		—
333 MHz		–390	390		—

Notes:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that will be captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW}. This can be determined by the following equation: t_{DISKEW} = ± (T/4 – abs(t_{CISKEW})), where T is the clock period and abs(t_{CISKEW}) is the absolute value of t_{CISKEW}. See Figure 3.
3. Maximum DDR1 frequency is 400 MHz.

Figure 3 shows the DDR SDRAM input timing diagram.

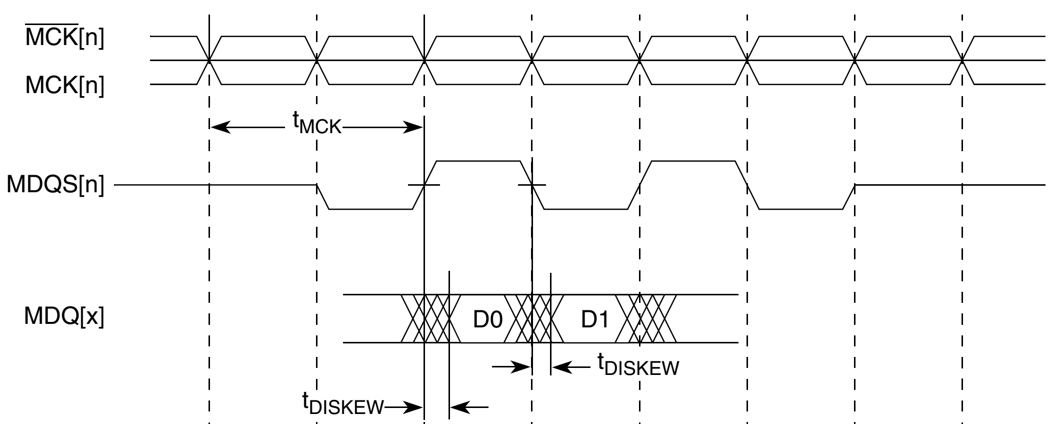


Figure 3. DDR SDRAM Input Timing Diagram (t_{DISKEW})

Table 24. DC Transmitter Electrical Characteristics (continued)

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Output differential voltage[2,3,5]	$\lvert V_{OD} \rvert$	323	500	725	mV	Equalization setting: 1.0x
		296	459	665		Equalization setting: 1.09x
		269	417	604		Equalization setting: 1.2x
		243	376	545		Equalization setting: 1.33x
		215	333	483		Equalization setting: 1.5x
		189	292	424		Equalization setting: 1.71x
		162	250	362		Equalization setting: 2.0x
Output offset voltage	V_{OS}	425	500	577.5	mV	1, 4
Output impedance (single ended)	R_O	40	—	60	Ω	—
Mismatch in a pair	ΔR_O	—	—	10	%	—
Change in V_{OD} between 0 and 1	$\Delta \lvert V_{OD} \rvert$	—	—	25	mV	—
Change in V_{OS} between 0 and 1	ΔV_{OS}	—	—	25	mV	—
Output current on short to GND	I_{SA}, I_{SB}	—	—	40	mA	—

Notes:

1. This will not align to DC-coupled SGMII.
2. $\lvert V_{OD} \rvert = \lvert V_{SD2\_TXn} - V_{\overline{SD2\_TXn}} \rvert$. $\lvert V_{OD} \rvert$ is also referred as output differential peak voltage. $V_{TX\text{-}DIFFp\text{-}p} = 2 * \lvert V_{OD} \rvert$.
3. The $\lvert V_{OD} \rvert$ value shown in the table assumes the following transmit equalization setting in the XMITEQ**CD** (for SerDes 2 lane 2 and 3) bit field of MPC8544E SerDes 2 control register 1:
   - The MSbit (bit 0) of the above bit field is set to zero (selecting the full $V_{DD\text{-}DIFF\text{-}p\text{-}p}$ amplitude—power up default);
   - The LSbits (bit [1:3]) of the above bit field is set based on the equalization setting shown in this table.
4. V_{OS} is also referred to as output common mode voltage.
5. The $\lvert V_{OD} \rvert$ value shown in the Typ column is based on the condition of $XV_{DD\_SRDS2\text{-}Typ}$ = 1.0 V, no common mode offset variation (V_{OS} = 500 mV), SerDes2 transmitter is terminated with 100-Ω differential load between SD2_TX[n] and SD2_TX[n].

Figure 7 shows an example of a 4-wire AC-coupled SGMII serial link connection.

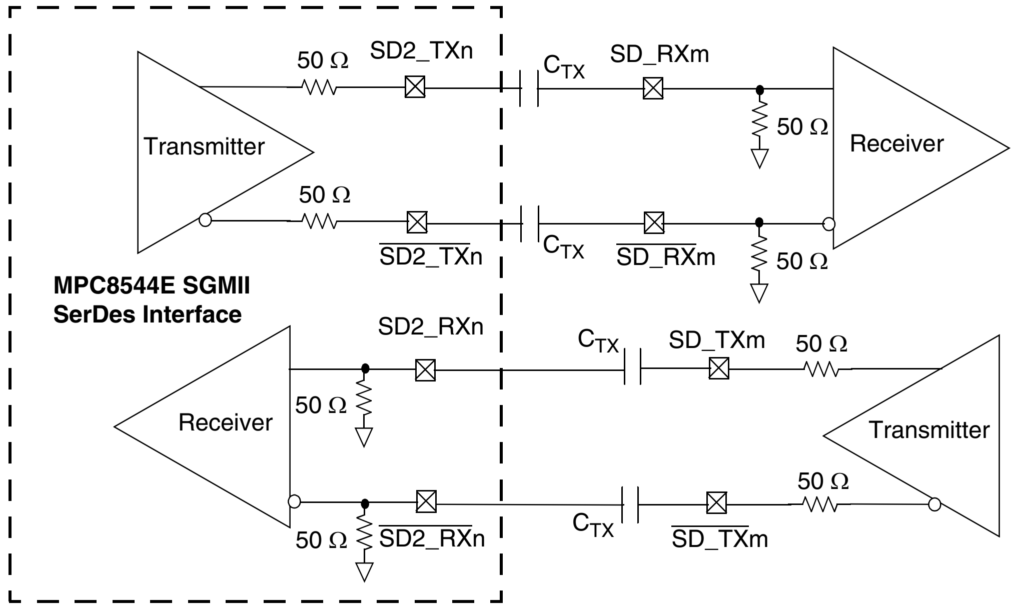


Figure 7. 4-Wire AC-Coupled SGMII Serial Link Connection Example

Figure 8 shows an SGMII transmitter DC measurement circuit.

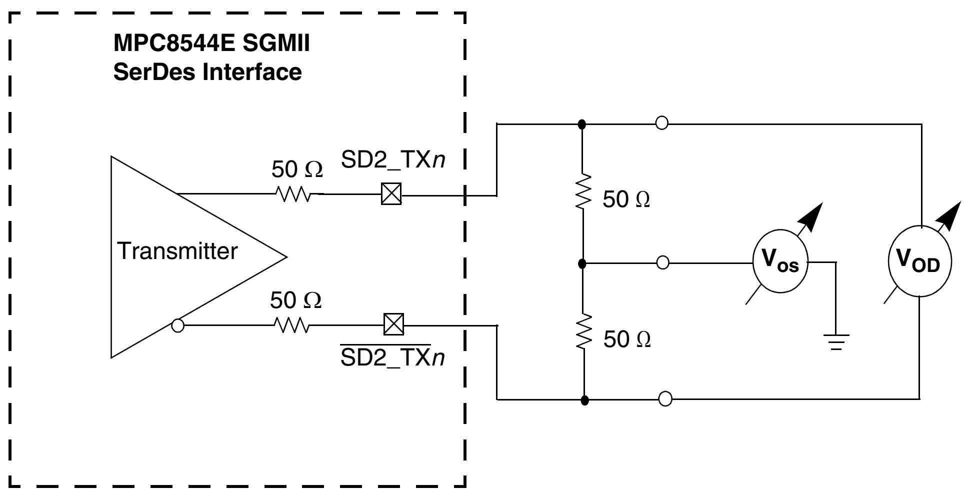


Figure 8. SGMII Transmitter DC Measurement Circuit

Table 25 shows the DC receiver electrical characteristics.

Table 25. DC Receiver Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Supply Voltage	V_{DD_SRDS2}	0.9	1.0	1.05	V	—
DC input voltage range	—	—	—	—	—	1

8.4.2 SGMII Receive AC Timing Specifications

Table 27 provides the SGMII receive AC timing specifications. Source synchronous clocking is not supported. Clock is recovered from the data. Figure 9 shows the SGMII receiver input compliance mask eye diagram.

Table 27. SGMII Receiver AC Timing Specifications

At recommended operating conditions with XVDD_SRDS2 = 1.0 V ± 5%.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic jitter tolerance	J_D	0.37	—	—	UI p-p	1
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	—	UI p-p	1
Sinusoidal jitter tolerance	Jsin	0.1	—	—	UI p-p	1
Total jitter tolerance	J_T	0.65	—	—	UI p-p	1
Bit error ratio	BER	—	—	10^{-12}	—	—
Unit interval	UI	799.92	800	800.08	ps	2
AC coupling capacitor	C_{TX}	5	—	200	nF	3

Notes:
1. Measured at receiver.
2. Each UI value is 800 ps ± 100 ppm.
3. The external AC coupling capacitor is required. It’s recommended to be placed near the device transmitter outputs.

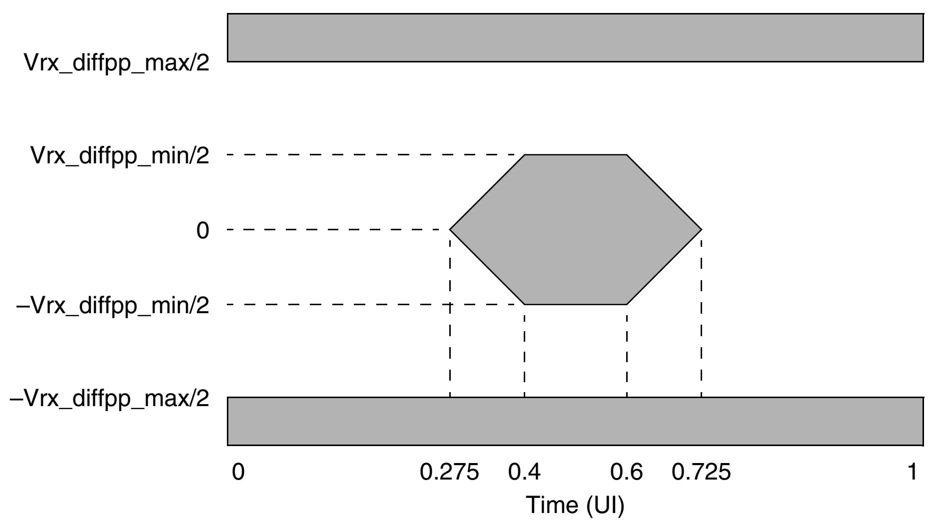


Figure 9. Receive Input Compliance Mask

8.7.1 TBI Transmit AC Timing Specifications

Table 34 provides the TBI transmit AC timing specifications.

Table 34. TBI Transmit AC Timing Specifications

At recommended operating conditions with L/TVDD of 3.3 V ± 5% or 2.5 V ± 5%

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
GTX_CLK clock period	t_{GTX}	—	8.0	—	ns	—
GTX_CLK to TCG[9:0] delay time	t_{TTKHDX}	0.2	—	5.0	ns	2
GTX_CLK rise (20%–80%)	t_{TTXR}	—	—	1.0	ns	—
GTX_CLK fall time (80%–20%)	t_{TTXF}	—	—	1.0	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Data valid t_{TTKHDV} to GTX_CLK Min setup time is a function of clock period and max hold time (Min setup = cycle time – Max delay).

Figure 19 shows the TBI transmit AC timing diagram.

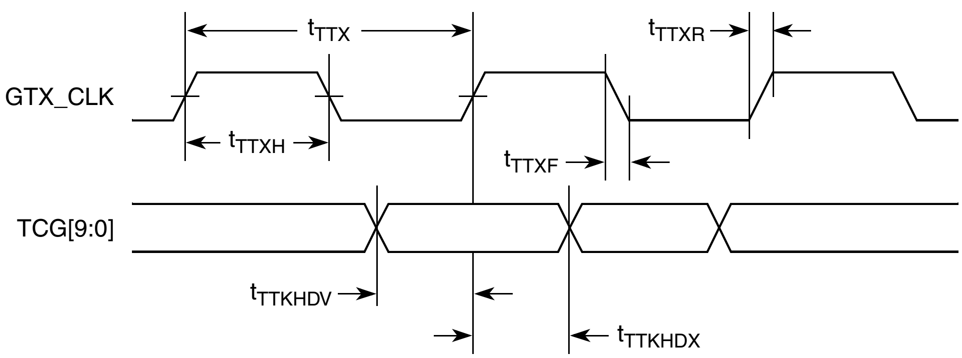


Figure 19. TBI Transmit AC Timing Diagram

8.7.2 TBI Receive AC Timing Specifications

Table 35 provides the TBI receive AC timing specifications.

Table 35. TBI Receive AC Timing Specifications

At recommended operating conditions with L/TVDD of 3.3 V ± 5% or 2.5 V ± 5%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
PMA_RX_CLK[0:1] clock period	t_{TRX}	—	16.0	—	ns	—
PMA_RX_CLK[0:1] skew	t_{SKTRX}	7.5	—	8.5	ns	—

Table 45. Local Bus General Timing Parameters (BV_{DD} = 3.3 V)—PLL Enabled (continued)

Parameter	Symbol[1]	Min	Max	Unit	Notes
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.5	ns	5

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.

Table 46 describes the general timing parameters of the local bus interface at BV_{DD} = 2.5 V.

Table 46. Local Bus General Timing Parameters (BV_{DD} = 2.5 V)—PLL Enabled

Parameter	Symbol[1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7
Input setup to local bus clock (except LUPWAIT)	$t_{LBIVKH1}$	2.4	—	ns	3, 4
LUPWAIT input setup to local bus clock	$t_{LBIVKH2}$	1.8	—	ns	3, 4
Input hold from local bus clock (except LUPWAIT)	$t_{LBIXKH1}$	1.1	—	ns	3, 4
LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.1	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH setup and hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.8	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.8	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.8	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.8	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.8	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.8	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5

Figure 28 through Figure 33 show the local bus signals.

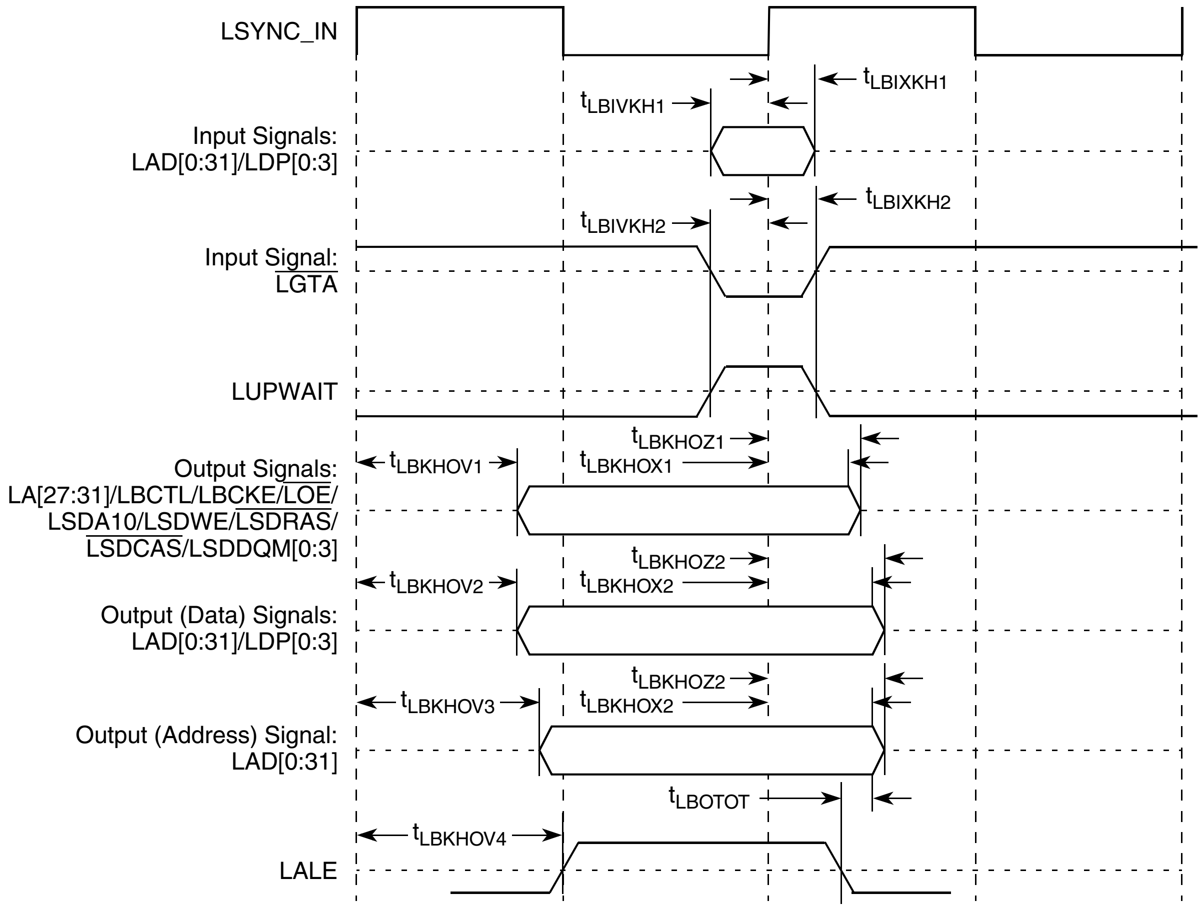


Figure 28. Local Bus Signals (PLL Enabled)

Table 48 describes the general timing parameters of the local bus interface at V_{DD} = 3.3 V DC with PLL disabled.

Table 48. Local Bus General Timing Parameters—PLL Bypassed

Parameter	Symbol[1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	12	—	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
Internal launch/capture clock to LCLK delay	t_{LBKHKT}	1.2	4.9	ns	—
Input setup to local bus clock (except LUPWAIT)	$t_{LBIVKH1}$	7.4	—	ns	4, 5
LUPWAIT input setup to local bus clock	$t_{LBIVKL2}$	6.75	—	ns	4, 5
Input hold from local bus clock (except LUPWAIT)	$t_{LBIXKH1}$	–0.2	—	ns	4, 5
LUPWAIT input hold from local bus clock	$t_{LBIXKL2}$	–0.2	—	ns	4, 5
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKLOV1}$	—	1.6	ns	—

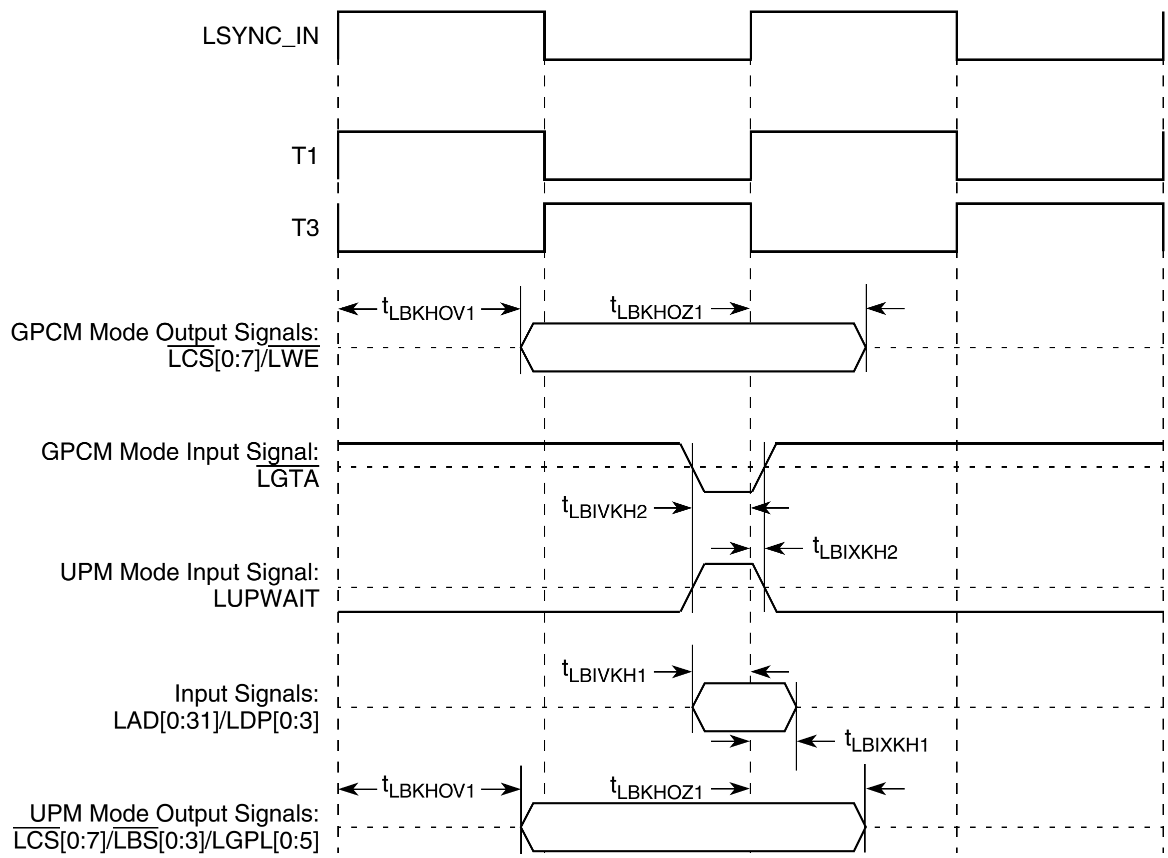


Figure 30. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (PLL Enabled)

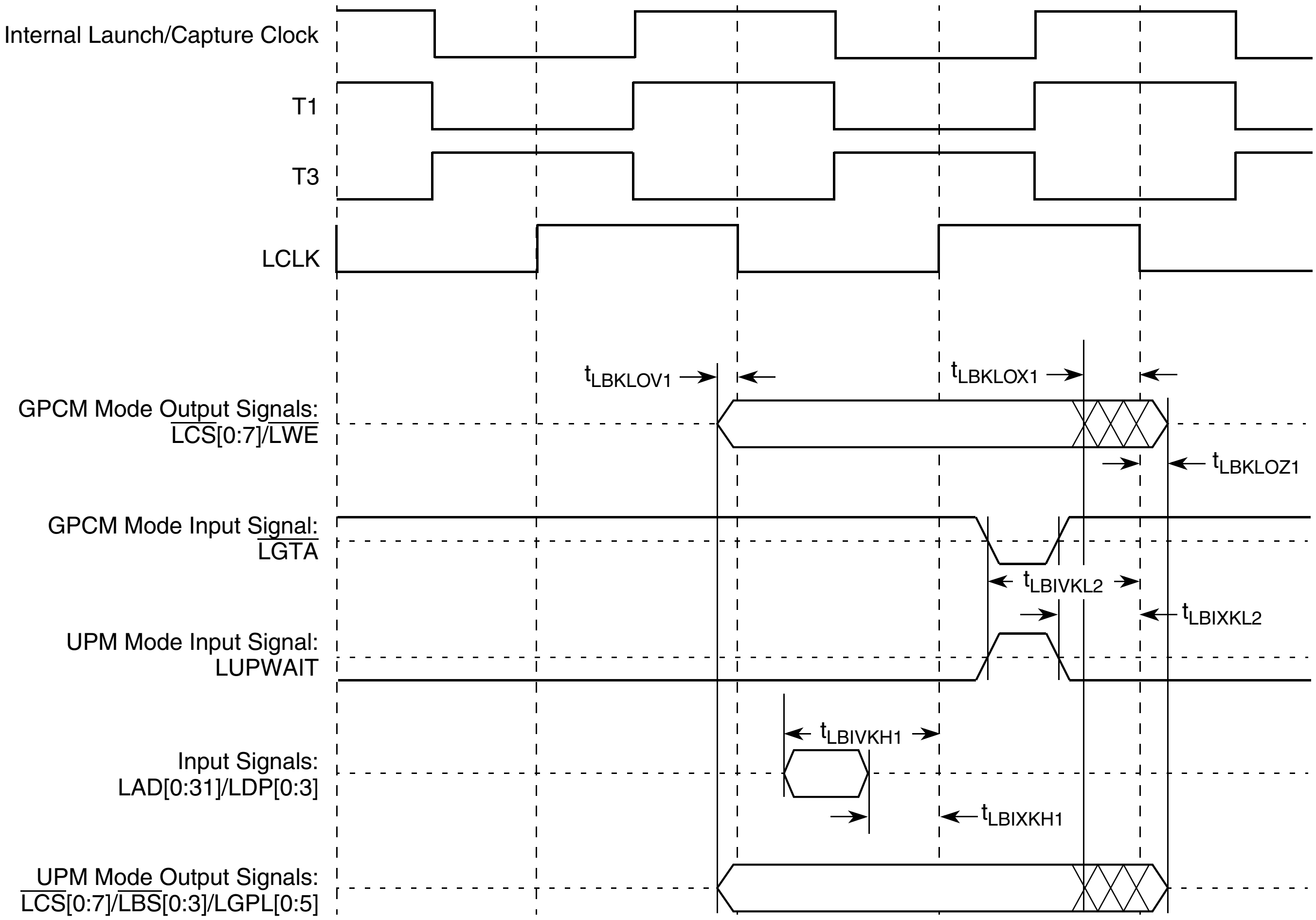


Figure 31. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (PLL Bypass Mode)

Figure 42 shows the PCI input AC timing conditions.

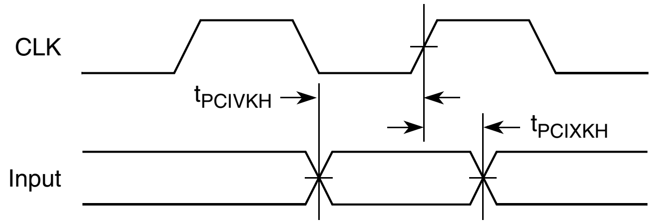


Figure 42. PCI Input AC Timing Measurement Conditions

Figure 43 shows the PCI output AC timing conditions.

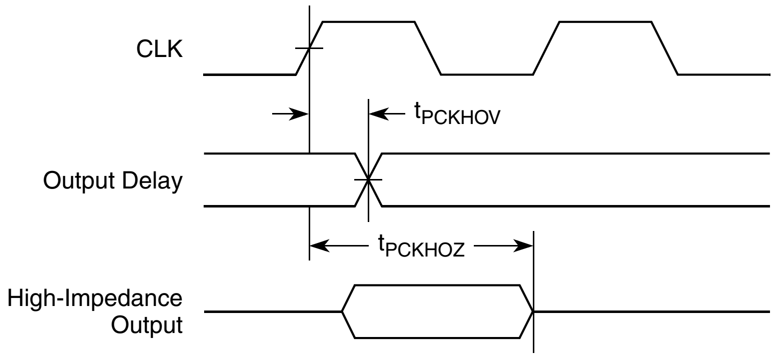


Figure 43. PCI Output AC Timing Measurement Condition

16 High-Speed Serial Interfaces (HSSI)

The MPC8544E features two serializer/deserializer (SerDes) interfaces to be used for high-speed serial interconnect applications.The SerDes1 dedicated for PCI Express data transfers. The SerDes2 can be used for PCI Express and/or SGMII application. This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes Reference Clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

16.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 44 shows how the signals are defined. For illustration purpose, only one SerDes lane is used for description. The figure shows waveform for either a transmitter output (SD*n*_TX and $\overline{\text{SD}n\text{\_TX}}$) or a receiver input (SD*n*_RX and $\overline{\text{SD}n\text{\_RX}}$). Each signal swings between A Volts and B Volts where A > B.

Table 60. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Units	Comments
$T_{RX\text{-}EYE\text{-}MEDIAN\text{-}to\text{-}MAX\text{-}JITTER}$	Maximum time between the jitter median and maximum deviation from the median	—	—	0.3	UI	Jitter is defined as the measurement variation of the crossing points ($V_{RX\text{-}DIFFp\text{-}p}$ = 0 V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2, 3, and 7.
$V_{RX\text{-}CM\text{-}ACp}$	AC peak common mode input voltage	—	—	150	mV	$V_{RX\text{-}CM\text{-}ACp} = \lvert V_{RXD+} - V_{RXD-}\rvert \div 2 - V_{RX\text{-}CM\text{-}DC}$ $V_{RX\text{-}CM\text{-}DC} = DC_{(avg)}$ of $\lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert/2$ See Note 2.
$RL_{RX\text{-}DIFF}$	Differential return loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at +300 and –300 mV, respectively. See Note 4.
$RL_{RX\text{-}CM}$	Common mode return loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at 0 V. See Note 4.
$Z_{RX\text{-}DIFF\text{-}DC}$	DC differential input impedance	80	100	120	Ω	RX DC differential mode impedance. See Note 5.
$Z_{RX\text{-}DC}$	DC input impedance	40	50	60	Ω	Required RX D+ as well as D– DC impedance (50 ± 20% tolerance). See Notes 2 and 5.
$Z_{RX\text{-}HIGH\text{-}IMP\text{-}DC}$	Powered down DC input impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC impedance when the receiver terminations do not have power. See Note 6.
$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$	Electrical idle detect threshold	65	—	175	mV	$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p} = 2 \times \lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert$ Measured at the package pins of the receiver.
$T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERTIME}$	Unexpected electrical idle enter detect threshold integration time	—	—	10	ms	An unexpected electrical idle ($V_{RX\text{-}DIFFp\text{-}p} < V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$) must be recognized no longer than $T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERING}$ to signal an unexpected idle condition.

Table 62. MPC8544E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{SD2\_REF\_CLK}}$	AF2	I	XV_{DD}	—
SD2_TST_CLK	AG4	—	—	—
$\overline{\text{SD2\_TST\_CLK}}$	AF4	—	—	—
General-Purpose Output				
GPOUT[0:7]	AF22, AH23, AG27, AH25, AF21, AF25, AG26, AF26	O	OV_{DD}	—
General-Purpose Input				
GPIN[0:7]	AH24, AG24, AD23, AE21, AD22, AF23, AG25, AE20	I	OV_{DD}	—
System Control				
$\overline{\text{HRESET}}$	AG16	I	OV_{DD}	—
$\overline{\text{HRESET\_REQ}}$	AG15	O	OV_{DD}	21
$\overline{\text{SRESET}}$	AG19	I	OV_{DD}	—
$\overline{\text{CKSTP\_IN}}$	AH5	I	OV_{DD}	—
$\overline{\text{CKSTP\_OUT}}$	AA12	O	OV_{DD}	2, 4
Debug				
TRIG_IN	AC5	I	OV_{DD}	—
TRIG_OUT/READY/ $\overline{\text{QUIESCE}}$	AB5	O	OV_{DD}	5, 8, 15, 21
MSRCID[0:1]	Y7, W9	O	OV_{DD}	4, 5, 8
MSRCID[2:4]	AA9, AB6, AD5	O	OV_{DD}	5, 15, 21
MDVAL	Y8	O	OV_{DD}	5
CLK_OUT	AE16	O	OV_{DD}	10
Clock				
RTC	AF15	I	OV_{DD}	—
SYSCLK	AH16	I	OV_{DD}	—
JTAG				
TCK	AG28	I	OV_{DD}	—
TDI	AH28	I	OV_{DD}	11
TDO	AF28	O	OV_{DD}	10
TMS	AH27	I	OV_{DD}	11
$\overline{\text{TRST}}$	AH22	I	OV_{DD}	11

Table 62. MPC8544E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
V_{DD}	L16, L14, M13, M15, M17, N12, N14, N16, N18, P13, P15, P17, R12, R14, R16, R18, T13, T15, T17, U12, U14, U16, U18,	Power for core (1.0 V)	V_{DD}	—
SVDD_SRDS	M27, N25, P28, R24, R26, T24, T27, U25, W24, W26, Y24, Y27, AA25, AB28, AD27	Core power for SerDes 1 transceivers (1.0 V)	SV_{DD}	—
SVDD_SRDS2	AB1, AC26, AD2, AE26, AG2	Core power for SerDes 2 transceivers (1.0 V)	SV_{DD}	—
XVDD_SRDS	M21, N23, P20, R22, T20, U23, V21, W22, Y20	Pad power for SerDes 1 transceivers (1.0 V)	XV_{DD}	—
XVDD_SRDS2	Y6, AA6, AA23, AF5, AG5	Pad power for SerDes 2 transceivers (1.0 V)	XV_{DD}	—
XGND_SRDS	M20, M24, N22, P21, R23, T21, U22, V20, W23, Y21	—	—	—
XGND_SRDS2	Y4, AA4, AA22, AD4, AE4, AH4	—	—	—
SGND_SRDS	M28, N26, P24, P27, R25, T28, U24, U26, V24, W25, Y28, AA24, AA26, AB24, AB27, AC24, AD28	—	—	—
AGND_SRDS	V27	SerDes PLL GND	—	—
SGND_SRDS2	Y2, AA1, AB3, AC2, AC3, AC25, AD3, AD24, AE3, AE1, AE25, AF3, AH2	—	—	—
AGND_SRDS2	AF1	SerDes PLL GND	—	—
AVDD_LBIU	C28	Power for local bus PLL (1.0 V)	—	19
AVDD_PCI1	AH20	Power for PCI PLL (1.0 V)	—	19
AVDD_CORE	AH14	Power for e500 PLL (1.0 V)	—	19
AVDD_PLAT	AH18	Power for CCB PLL (1.0 V)	—	19

Table 62. MPC8544E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
AVDD_SRDS	W28	Power for SRDSPLL (1.0 V)	—	19
AVDD_SRDS2	AG1	Power for SRDSPLL (1.0 V)	—	19
SENSEVDD	W11	O	V_{DD}	12
SENSEVSS	W10	—	—	12
Analog Signals				
MVREF	A28	Reference voltage signal for DDR	MVREF	—
SD1_IMP_CAL_RX	M26	—	200Ω to GND	—
SD1_IMP_CAL_TX	AE28	—	100Ω to GND	—
SD1_PLL_TPA	V26	—	AVDD_SRDS ANALOG	17
SD2_IMP_CAL_RX	AH3	I	200 Ω to GND	—
SD2_IMP_CAL_TX	Y1	I	100 Ω to GND	—
SD2_PLL_TPA	AH1	O	AVDD_SRDS2 ANALOG	17
No Connect Pins				
NC	C19, D7, D10, K13, L6, K9, B6, F12, J7, M19, M25, N19, N24, P19, R19, AB19, T12, W3, M12, W5, P12, T19, W1, W7, L13, U19, W4, V8, V9, V10, V11, V12, V13, V14, V15, V16, V17, V18, V19, W2, W6, W8, T11, U11, W12, W13, W14, W15, W16, W17, W18, W19, W27, V25, Y17, Y18, Y19, AA18, AA19, AB20, AB21, AB22, AB23, J9	—	—	—

Notes:

1. All multiplexed signals are listed only once and do not re-occur. For example, $\overline{\text{LCS5}}$/$\overline{\text{DMA\_REQ2}}$ is listed only once in the Local Bus Controller Interface section, and is not mentioned in the DMA section even though the pin also functions as $\overline{\text{DMA\_REQ2}}$.
2. Recommend a weak pull-up resistor (2–10 KΩ) be placed on this pin to OV_{DD}.
3. This pin must always be pulled high.
4. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pull-up or active driver is needed. TSEC3_TXD[3] (cfg_srds_sgmii_refclk) is an exception, because the default value of this configuration signal is low (0). Thus, no external pull-down resistor is needed for selecting the default configuration value.
5. Treat these pins as no connects (NC) unless using debug address functionality.

where:

I_{fw} = Forward current

I_s = Saturation current

V_d = Voltage at diode

V_f = Voltage forward biased

V_H = Diode voltage while I_H is flowing

V_L = Diode voltage while I_L is flowing

I_H = Larger diode bias current

I_L = Smaller diode bias current

q = Charge of electron (1.6×10^{-19} C)

n = Ideality factor (normally 1.0)

K = Boltzman's constant (1.38×10^{-23} Joules/K)

T = Temperature (Kelvins)

The ratio of I_H to I_L is usually selected to be 10:1. The above simplifies to the following:

$$\mathbf{V_H - V_L = 1.986 \times 10^{-4} \times nT}$$

Solving for T, the equation becomes:

$$\mathbf{nT} = \frac{V_H - V_L}{1.986 \times 10^{-4}}$$

21 System Design Information

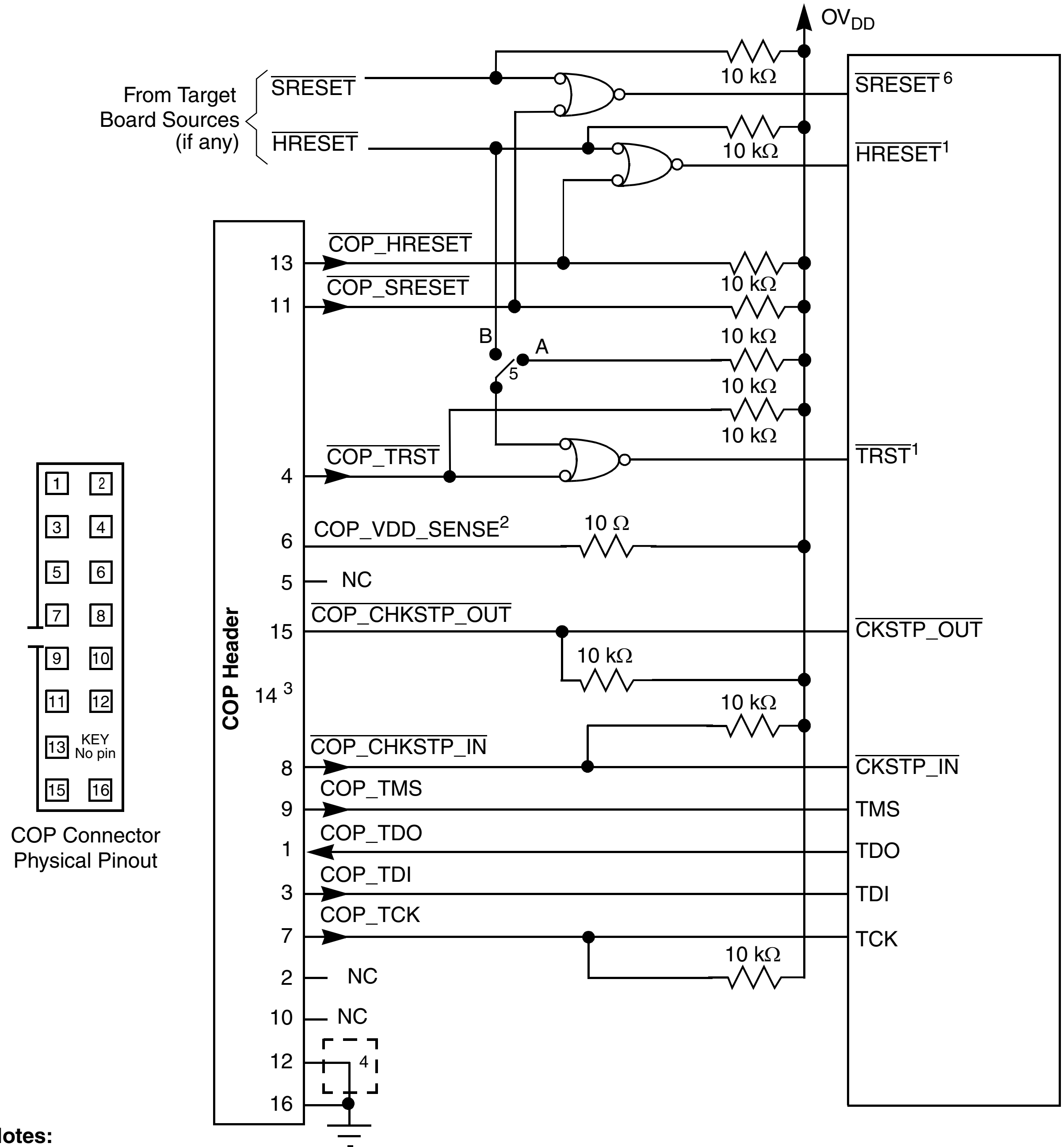
This section provides electrical and thermal design recommendations for successful application of the MPC8544E.

21.1 System Clocking

This device includes six PLLs:

- The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 19.2, “CCB/SYSCLK PLL Ratio.”
- The e500 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e500 core clock and the platform clock is selected using the e500 PLL ratio configuration bits as described in Section 19.3, “e500 Core PLL Ratio.”
- The PCI PLL generates the clocking for the PCI bus.
- The local bus PLL generates the clock for the local bus.
- There are two PLLs for the SerDes block.

Figure 69 shows the JTAG interface connection.



Notes:
1. The COP port and target board should be able to independently assert HRESET and TRST to the processor in order to fully control the processor as shown here.
2. Populate this with a 10-Ω resistor for short-circuit/current-limiting protection.
3. The KEY location (pin 14) is not physically present on the COP header.
4. Although pin 12 is defined as a No Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
5. This switch is included as a precaution for BSDL testing. The switch should be closed to position A during BSDL testing to avoid accidentally asserting the TRST line. If BSDL testing is not being performed, this switch should be closed to position B.
6. Asserting SRESET causes a machine check interrupt to the e500 core.

Figure 69. JTAG Interface Connection